Microscopy TODAY

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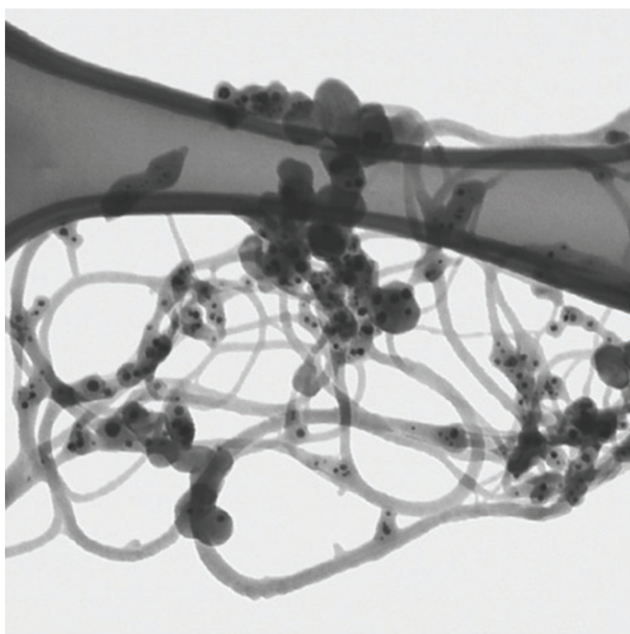

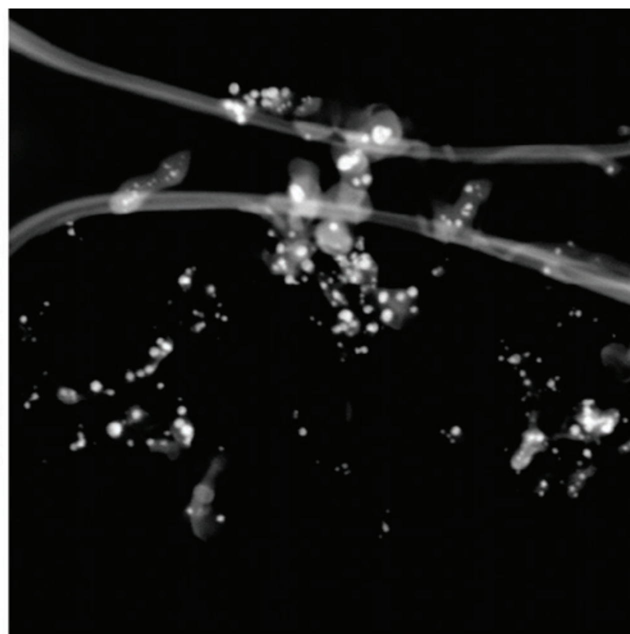

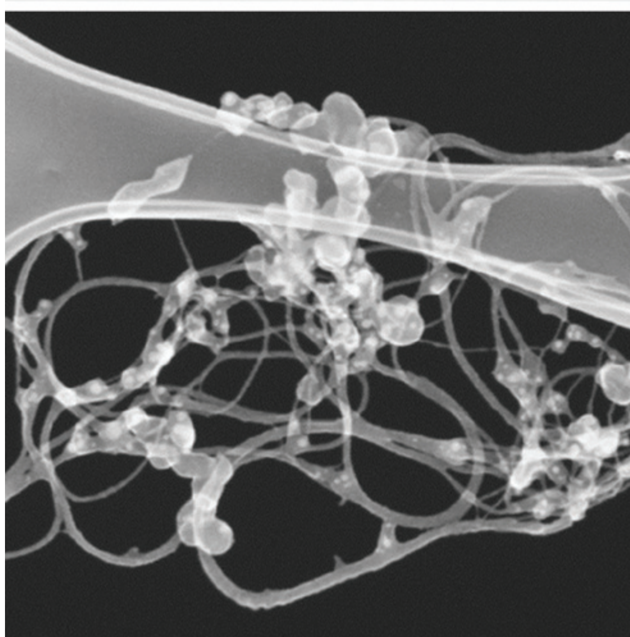

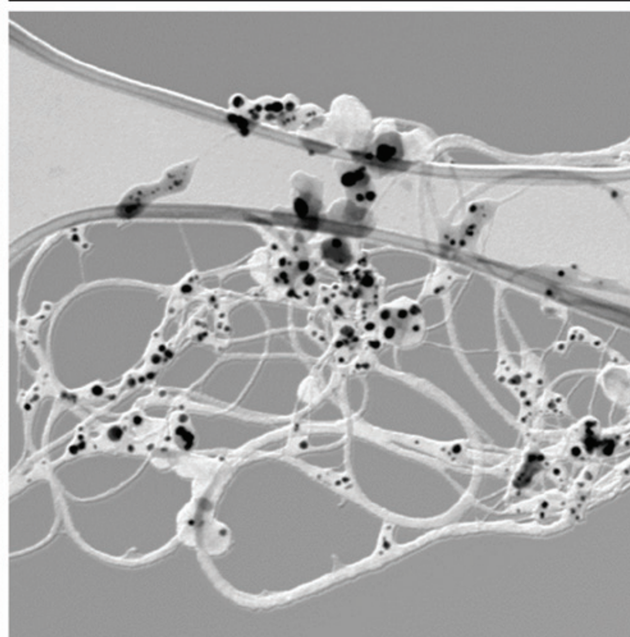

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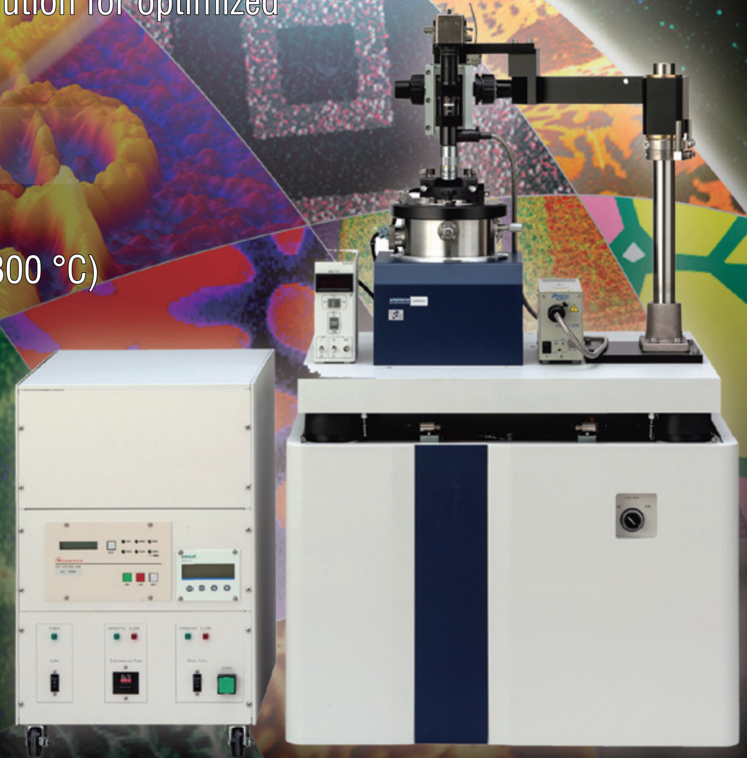

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FEI Avizo® 3D visualization of two large adjacent crystalline dendrites of a bulk-metallic-glass matrix composite ($Zr_{58.5}Ti_{14.3}Nb_{5.2}Cu_{6.1}Ni_{4.9}Be_{11.0}$). Data was obtained by large volume serial sectioning tomography using the Helios PFIB DualBeam. The sectioned block is about 90×80×70 μm³. Sample from The University of Tennessee, USA. Images courtesy of The University of Manchester.

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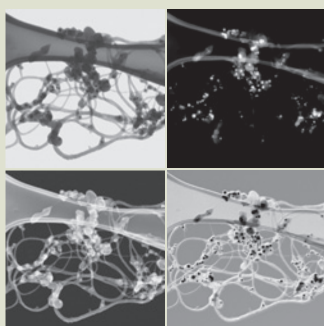

SEM images of single-wall carbon nanotube bundles with metal catalyst particles. Clockwise from upper left: brightfield STEM, high-angle annular darkfield STEM, marginal brightfield STEM, and secondary electron mode. Image width = 1 µm.

See article by Holm and Keller

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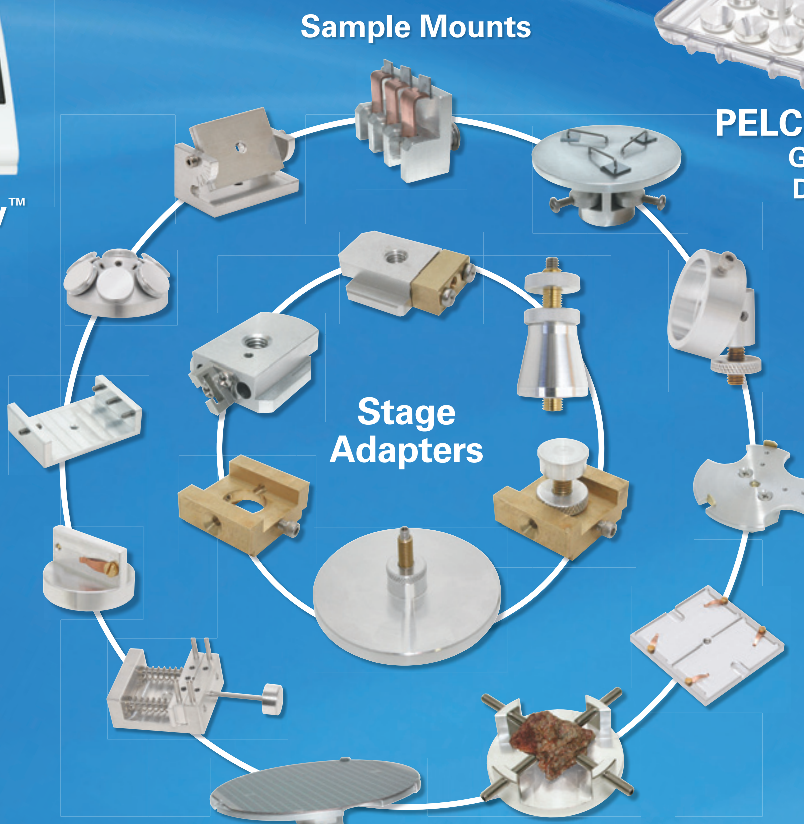

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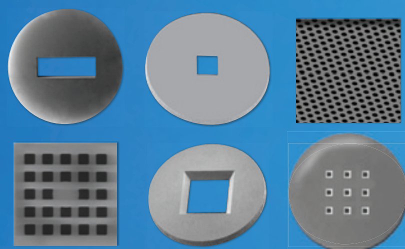

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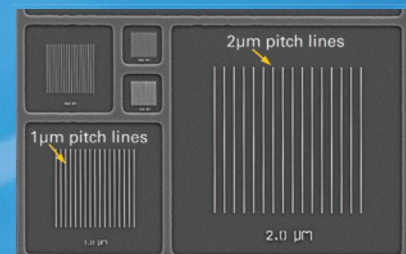

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